

# Effect of combination of twist pitches on distribution of strands appearing on cable surface in CICC

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# **Outline**

- 1. Background and Objective
- 2. Experiment of a resistance distribution between strands and a copper sleeve at LHe temperature
- Calculation of a resistance distribution between strands and a copper sleeve using computed strand paths
- 4. Influence of a combination of twist pitches on a distribution of strands appearing on cable surface
- 5. Summary



#### Background and Objective

Superconducting coils used for fusion reactors and SMES are formed from a Cable-in-Conduit-Conductor (CICC).

#### i. Cable-in-Conduit Conductor (CICC)

- ✓ Composed of many superconducting strands twisted in multiple stages (usually 4~5 stages) for large current capacity.
- ✓ Strands are compacted into a metallic conduit for high mechanical strength.



CICC

#### However, .....

✓ Critical current of a CICC is lower than the expected.



partly explained by filament fracture and unbalanced current.



#### Background and Objective

One of the reasons is unbalanced current distribution caused by inhomogeneous contact resistances between a copper sleeve and strands at joint called "wrap joint".

#### ii. CICC Joint (Wrap Joint)

- √ Two cables without conduit are inserted into a copper sleeve to join each other.
- ✓ Strands are in contact with a copper sleeve on the cable surface.
- ✓ Current flow between two CICCs through a copper sleeve.

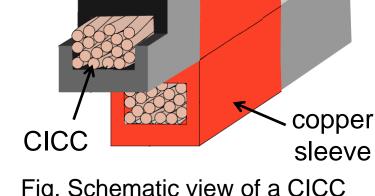


Fig. Schematic view of a CICC wrap joint.

- ✓ Contact condition between a strand and a copper sleeve was estimated to be inhomogeneous by our calculation.
- It has been unclear that the resistance distribution between strands and a copper sleeve is inhomogeneous actually.



#### Objective of this study

- √The resistance distribution becomes inhomogeneous?
- √The resistance distribution relates to contact condition?

We examined the influence of a combination of twist pitches on a distribution of strands appearing on cable surface using the calculated strand paths.



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#### Specifications of Measurement Sample



CICC (LHD OV coil)

number of strands	486
material of strand	NbTi / Cu
strand diameter [mm]	0.89
cable size [mm]	20.5 × 24.8
cable twist pitch [mm]	70/120/170/250/400



length [mm]	75
size [mm]	18.8 × 23.0

The inner shape of the sleeve was designed such that <u>the</u> void fraction of the CICC changed from 38% to 30%.

**Copper Sleeve** 



	thickness [mm]	50
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**Indium Sheet** 

(Simulates the solder coating)



#### Simple model "Wrap Joint"

- 1. A conduit and a stainless wrap were removed at one end of a sample.
- 2. The conduit and the stainless wrap were removed within 75mm in length.
- 3. A thin indium sheet was wrapped around the cable.

  The wrap of indium sheet simulated the solder coating in a real wrap joint.
- 4. The copper sleeve was installed on the cable with the indium sheet.

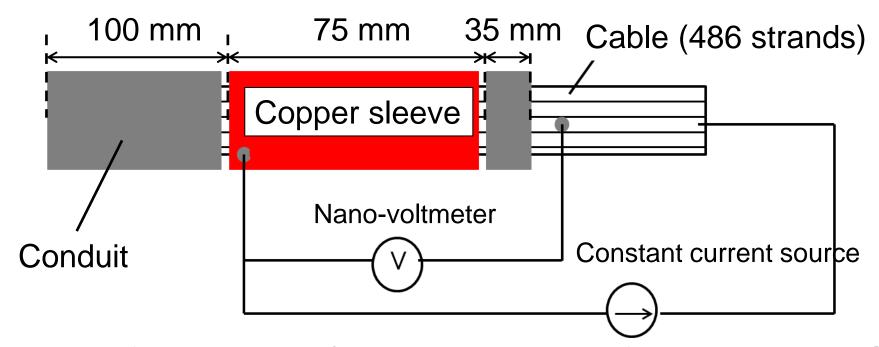


Fig. Schematic view of a measurement sample arrangement.



#### Simple model "Wrap Joint"

We measured the contact resistance between the copper sleeve and each strand using the four-terminal method at the LHe temperature (4.2K).

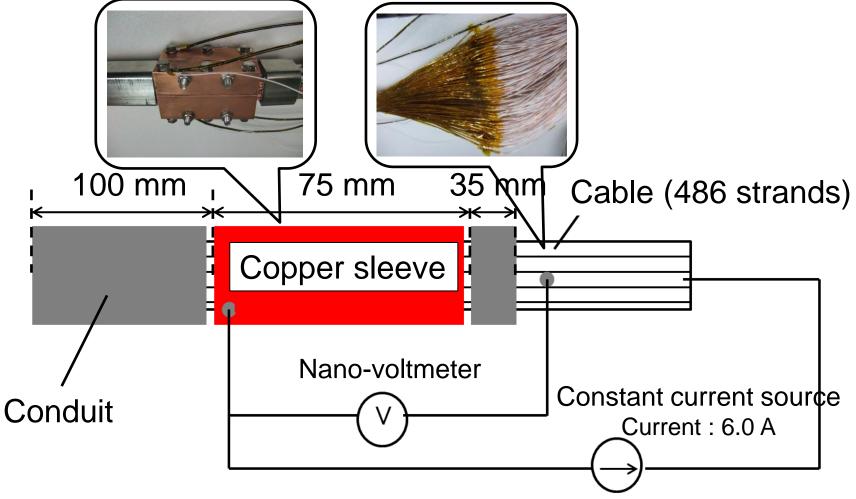
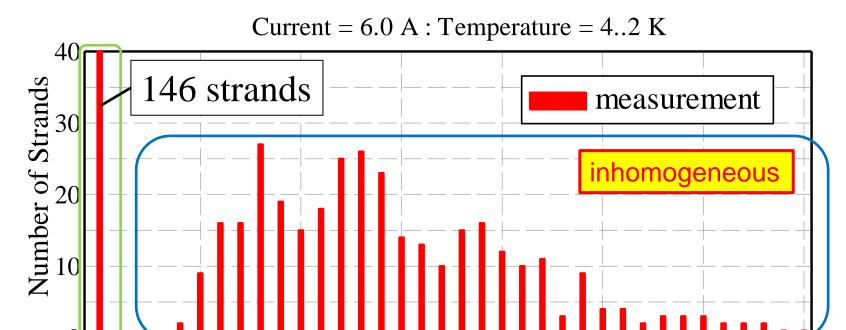


Fig. Schematic view of a measurement sample.



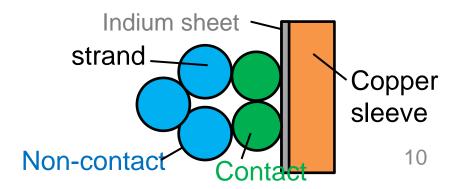
#### Measurement Results



Resistance between the strand and the copper sleeve  $\; [\mu\Omega] \;$  Fig. Measurement resistance distribution between the strands and the copper sleeve.

0.4

The 0 ohm strands are considered to be in direct contact with the copper sleeve through the indium sheet.





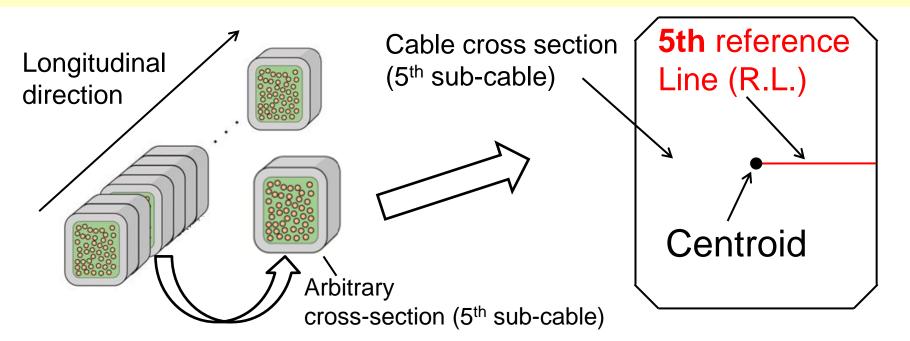
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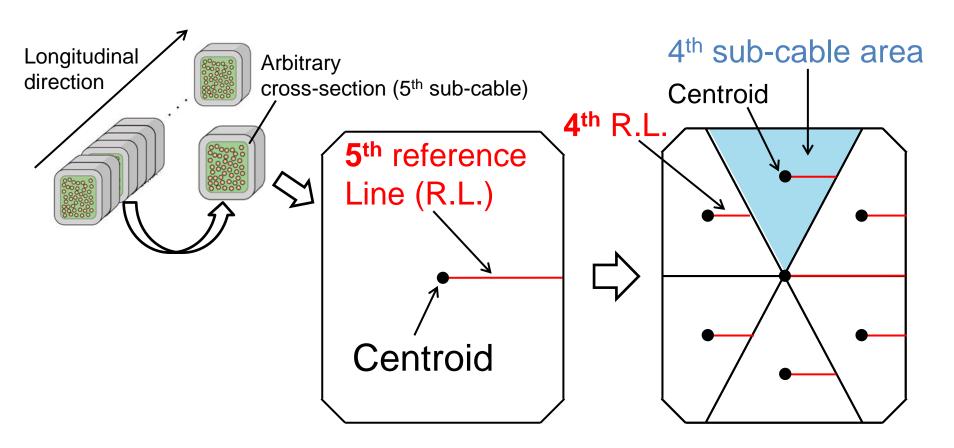
In order to calculate the resistance distribution between the strands and the copper sleeve, we evaluated all strand paths by numerical approach considering the manufacturing process of the CICC. Equal-area method

#### We evaluated all strand positions at each cross-section every 10mm.



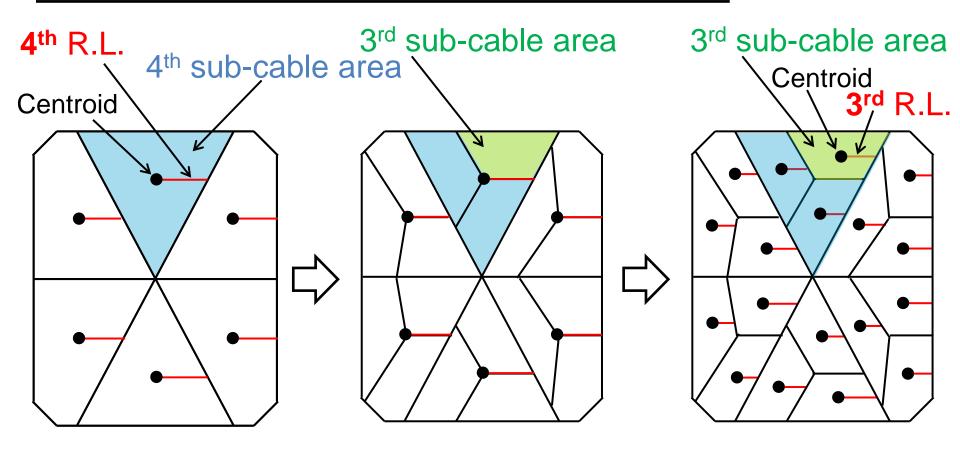
- 1. Draw the outer shape of the 5<sup>th</sup> sub-cable in the cross section of a sample CICC.
- 2. Draw a "reference line" from the 5th sub-cable centroid to the outer shape.





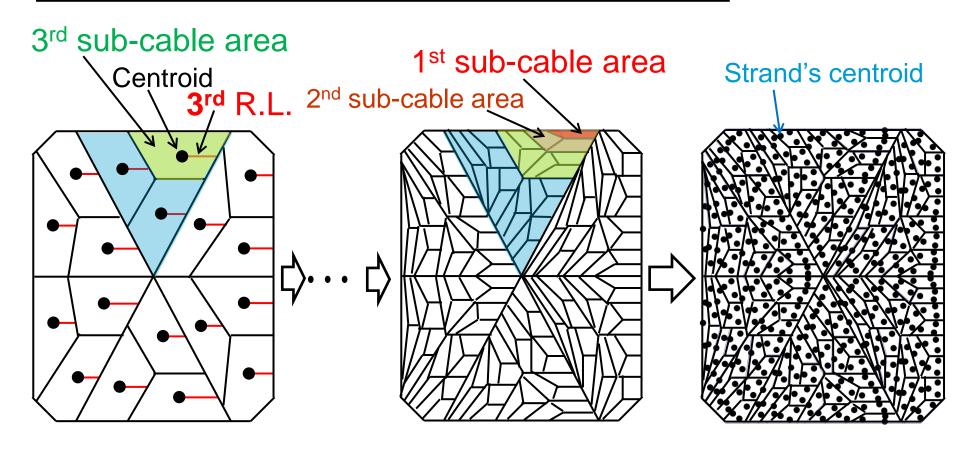
- 3. Divide the cross section (5<sup>th</sup> sub-cable) into six 4<sup>th</sup> sub-cables with same area on the basis of the 5<sup>th</sup> reference line. Because the same order sub-cables consist of the same number of strands.
- 4. Draw a "4<sup>th</sup> reference line" from the 4<sup>th</sup> sub-cable centroid to the outer shape of the 4<sup>th</sup> sub-cable in each 4<sup>th</sup> sub-cable area.





- 5. Divide each 4<sup>th</sup> sub-cable area into three 3<sup>rd</sup> sub-cables with same area on the basis of the 4<sup>th</sup> reference line.
- 6. Draw a "3<sup>rd</sup> reference line" from the 3<sup>rd</sup> sub-cable centroid to the outer shape of the 3<sup>rd</sup> sub-cable in each 3<sup>rd</sup> sub-cable area.





- 7. Divide each 3<sup>rd</sup> sub-cable area into three 2<sup>nd</sup> sub-cables with same area.
- 8. Similarly, divide each 2<sup>nd</sup> sub-cable area into three 1<sup>st</sup> sub-cables with same area.
- divide each 1<sup>st</sup> sub-cable area into three strands and obtain all strands' centroid's position at the cross-section of the cable.



10. Rotate each sub-cable about its centroid. The rotation angle depends on the longitudinal position (z). The rotating angle  $\theta_n$  of n-th order sub-cable is given as follows:  $n: R.L. \text{ order } (1\sim5)$ 

$$\theta_n = \theta_{n0} + \frac{2\pi}{p_n} z$$

 $\theta_n$ : rotation angle of *n*-th R.L.

 $\theta_{n0}$ : initial rotation angle of *n*-th R.L.

 $P_n$ : twist pitch of *n*-th sub-cable

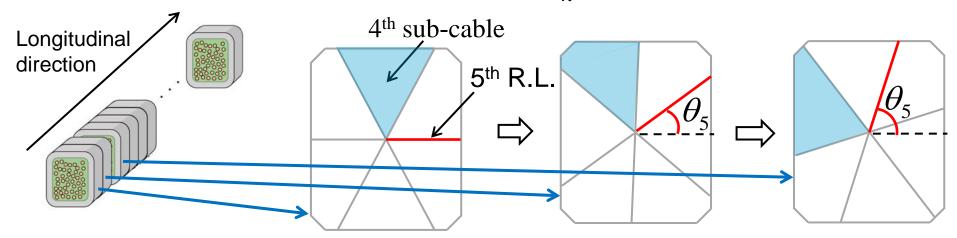


Fig. Schematic view of 5<sup>th</sup> reference line and 4<sup>th</sup> sub-cables' rotation at a cross-section.

The cable contraction due to refrigerant cooling was not considered in this method.



Our technique "equal-area method" to evaluate strand's positions ignores the overlap among strands. However, actual strands do not overlap, and each strand's

accumulated in the strands.

contact region is pressurized. In this situation, the elastic potential energy is In addition, the elastic potential energy is also accumulated by the deformation of the twist structure of strands.

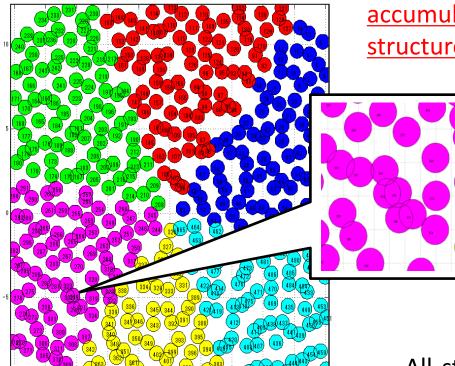


We introduce the elastic potential energy into our method.

We search strand's positions with the minimum elastic potential energy.

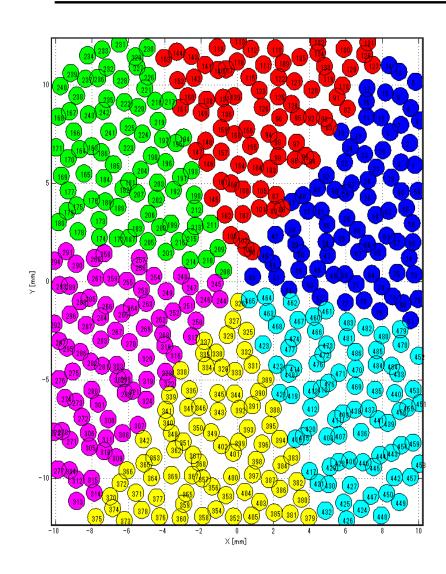


All strand's positions evaluated by "equal-area method" are iteratively perturbed using a genetic algorithm until the elastic potential energy in the cross section is minimized.

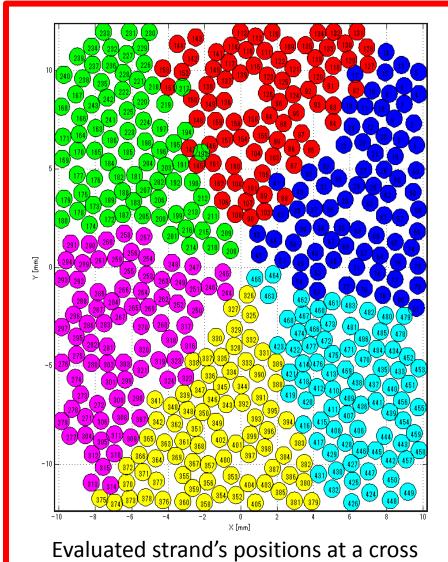


Evaluated strands' positions at a cross section by "equal-area method".





Evaluated strand's positions at a cross section by only "equal-area method".



Evaluated strand's positions at a cross section in consideration of the elastic potential energy minimization.

#### Calculation of the Contact Resistance

- We assumed the contact resistance between a strand and a copper sleeve to be 0 Ω according to our experimental results.
- We assumed that the contact resistance "R<sub>c</sub>" between strands only depends on the contact length.
- The contact length " $I_c$ " between two strands was considered as the sum total of partial contact length.
- The contact conductance between the strands " $G_c$ " was obtained by

$$G_c = G_a \times l_c$$

 $G_c$ : contact conductance [S]

 $G_a$ : constant value [S/m]

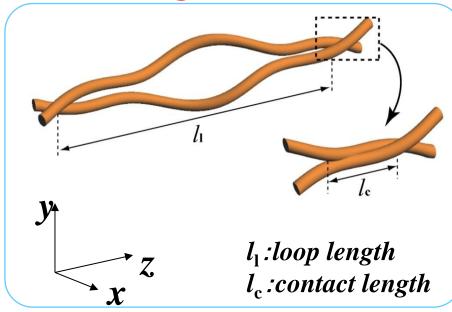


Fig. Schematic view of two strands contacting each other.

# Resemblance between the resistance distribution

The calculated resistance distribution between the strands and the copper sleeve depends on the value "Ga" and contact length.

We analyzed the similarity between the calculated resistance distribution and the measured one using "cosine similarity" as a function of " $G_a$ ".

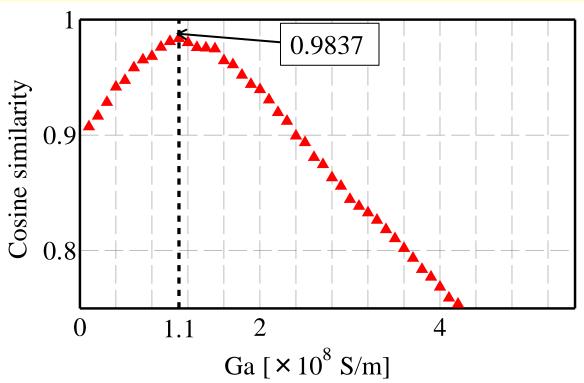
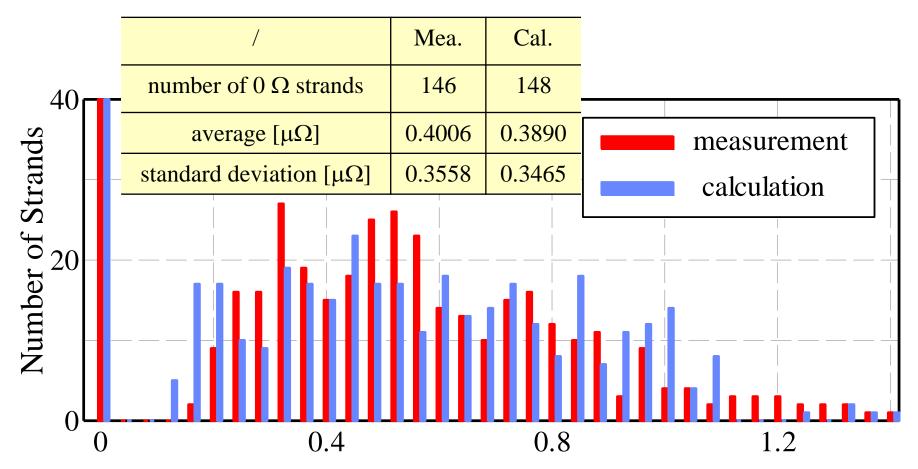


Fig. The relation between the cosine similarity and "Ga" contact conductance per meter between strands.

### Comparison of Resistance Distribution

Tab. Characteristics of measured and calculated resistance distribution.



Resistance between the strand and the copper sleeve  $[\mu\Omega]$ 

Fig. The comparison of the calculated resistance distribution with the measured resistance distribution between the strand and the copper sleeve.

## Comparison of Resistance Distribution

The homogeneity of the resistance distribution between the copper sleeve and strands is strongly dependent on whether the strand is in direct contact with the copper sleeve or not.

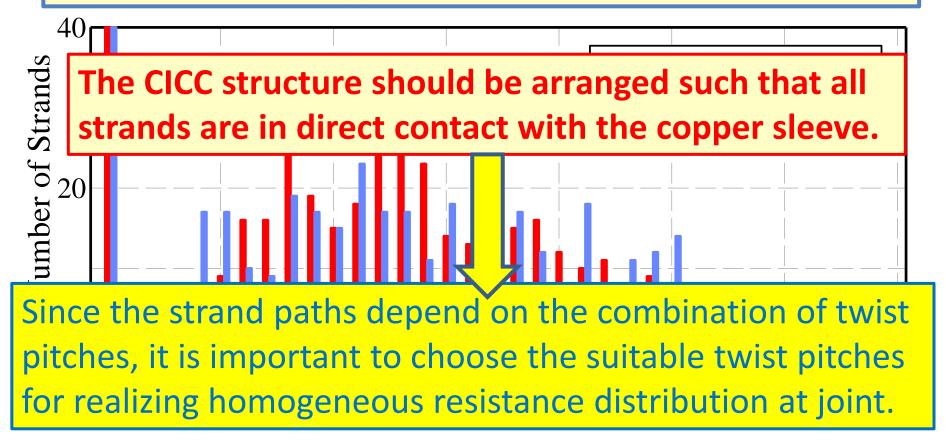


Fig. The comparison of the calculated resistance distribution with the measured resistance distribution between the strand and the copper sleeve.



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#### Influence of Twist Pitch on Contact Situation

Tob Chapitians of analyzed model of a CICC

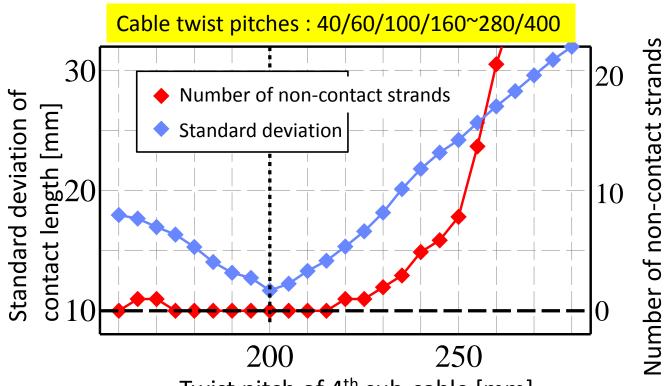
lab. Specifications of analyzed model of a CICC.	
number of strands	486
strand diameter [mm]	0.89
cable size [mm]	20.5 × 24.8
Cable length [mm]	400
Actual model :cable twist pitch [mm]	70/120/170/250/400
Analyzed model :cable twist pitch [mm]	<b>40/60/100/<u>160~280</u>/4</b> 00
Copper sleeve length [mm]	400
Copper sleeve inner size [mm]	18.8 × 23.0

- It has been reported that a contact situation is improved between a strand and a copper sleeve when twist pitches have been shorter.
- The strand has the degradation of the critical current when twist pitches of 1<sup>st</sup> and 2<sup>nd</sup> sub-cable are shortened too much.

We investigated the influence of the combination of twist pitches of each sub-cable on contact length between the strand and the copper sleeve by varying the twist pitch of the 4<sup>th</sup> sub-cable from 160 to 280 mm.



# Influence of Twist Pitch on Contact Situation



<Actual model>

Number of noncontact strands : 66

Standard deviation of contact length : 32.54 mm

Twist pitch of 4<sup>th</sup> sub-cable [mm]

Fig. Influence of the twist pitch of the 4<sup>th</sup> sub-cable on contact situation between strands and the copper sleeve.

All strands are in contact with the copper sleeve and standard deviation of contact length between strands and the copper sleeve becomes the minimum, when twist pitches of 3rd and 4th sub-cables are aliquot part of a twist pitch of a 5th sub-cable.



#### <u>Summary</u>

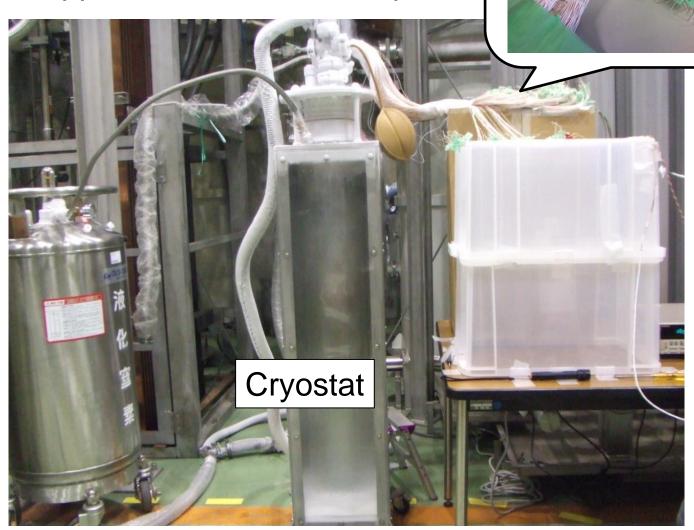
- We measured the contact resistance between the copper sleeve and each strand at a joint which simulated the wrap joint.
  - The non-uniformity of contact resistances between the copper sleeve and the strands was observed.
  - The homogeneity of the resistance distribution between the copper sleeve and strands is strongly dependent on whether the strand is in direct contact with the copper sleeve or not.
- The CICC structure should be arranged such that all strands are in directly contact with a copper sleeve at a joint.
  - It is expected that the resistance distribution between the strand and the copper sleeve is homogeneous, when twist pitches of 3<sup>rd</sup> and 4<sup>th</sup> sub-cables are aliquot part of a twist pitch of a 5<sup>th</sup> sub-cable.



# Thank you for your attention.

#### Measurement system

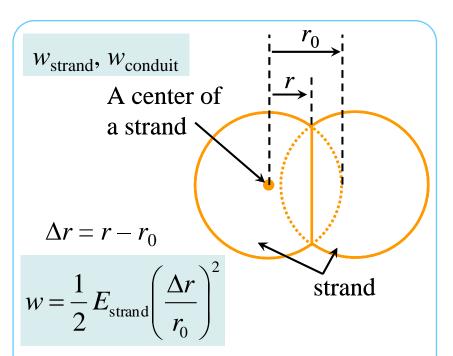
We measured the resistance distribution and the copper sleeve at LHe temperatu



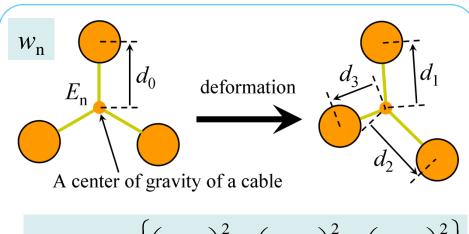
#### Calculation of Elastic Potential Energy

#### calculate following component in each section

 $extstyle W_{strand}$ ,  $W_{conduit}$  energy of strand deformation by strand and conduit  $extstyle W_n$  energy of n stage sub-cable's deformation



 $E_{\text{strand}}$ : Young's modulus of strand



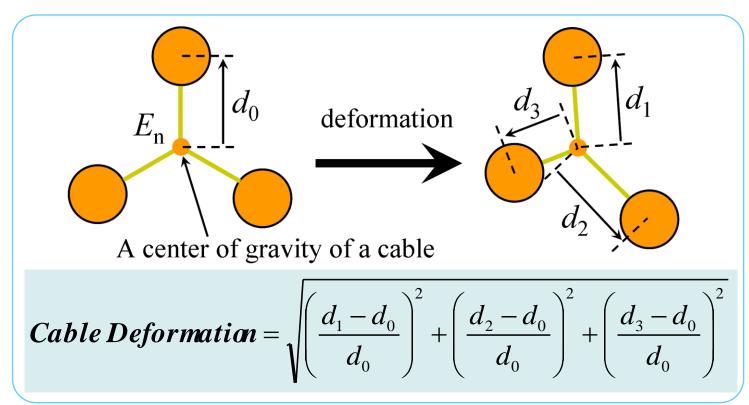
$$w_{\rm n} = \frac{1}{2} E_{\rm n} \left\{ \left( \frac{\Delta d_1}{d_0} \right)^2 + \left( \frac{\Delta d_2}{d_0} \right)^2 + \left( \frac{\Delta d_3}{d_0} \right)^2 \right\}$$

 $E_{\rm n}$ : hypothetical elastic modulus (simulate twist under 3D component )

#### Evaluation of strands' positions

Evaluate all strands' positions in each section by

- **1** 1st Sub-Cable (triplet) Deformation
- **☑**Loop Length between strands
- **✓** Contact Length between strands



Schematic view of deformation of a triplet at a cross section.